## **Amendments to the Specification:**

Please replace the paragraph on page 17, lines 20-29 with the following amended paragraph:

Overview. The currently preferred embodiment of a system for implementation of the present invention is an array system in which a 2-D-CCD-a 2-Dimensional Charge Coupled Device (2-D CCD) detector is used to image a sample chip containing 100-400 or more ROIs. Quasi-monochromatic light from a filtered, p-polarized LED (light-emitting diode) is used for illumination. The angle of incidence of the light beam on the chip is varied by mechanically scanning the light source. For each angle of incidence, one or more CCD frame exposures are used to perform a simultaneous measurement of the reflected light intensities for all the members of the ROI array. While the preferred embodiment of the EPF system of the present invention is specifically targeted toward such array systems, it works equally well on single or few channel instruments.